

FQP20N06L-VB Datasheet N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a			
60	0.024 at V _{GS} = 10 V	50			
	0.028 at V _{GS} = 4.5 V	40			

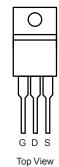
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC

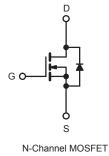


RoHS'

COMPLIANT



TO-220AB



ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)						
PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-Source Voltage	V _{DS}	60	V			
Gate-Source Voltage	V _{GS}	± 20	v			
Continuous Drain Current ^f	$-V_{GS}$ at 10 V $\frac{T_{C} = 25 \circ C}{T_{C} = 100 \circ C}$		50			
Continuous Drain Current	$T_{\rm C} = 100^{\circ}$		36	А		
Pulsed Drain Current ^a	Drain Current ^a					
Linear Derating Factor		1.0	W/°C			
Linear Derating Factor (PCB Mount)e		0.025	WV/C			
Single Pulse Avalanche Energy ^b	E _{AS}	400	mJ			
Maximum Power Dissipation	T _C = 25 °C	Р	150	W		
Maximum Power Dissipation (PCB Mount)e	T _A = 25 °C		3.7			
Peak Diode Recovery dV/dt ^c	dV/dt	4.5	V/ns			
Operating Junction and Storage Temperature Range	TJ, Tstg	T _J , T _{stg} - 55 to + 175	- °C			
Soldering Recommendations (Peak Temperature) ^d	for 10 s		300 ^d	C		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, $L = 179 \text{ }\mu\text{H}$, $R_g = 25 \Omega$, $I_{AS} = 51 \text{ A}$ (see fig. 12). c. $I_{SD} \le 51 \text{ A}$, dl/dt $\le 250 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 175 \text{ °C}$.

e. When mounted on 1" square PCB (FR-4 or G-10 material).

f. Current limited by the package, (die current = 51 A).

d. 1.6 mm from case.

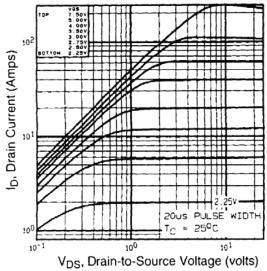


PARAMETER	NGS SYMBOL	TYP		MAX.			UNIT	
Maximum Junction-to-Ambient		IYP	•			UNII		
Maximum Junction-to-Ambient Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA} R _{thJA}	-		62 40		°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 1.0						
ote	" thJC			1.0				
When mounted on 1" square PCB (FR-4 of	or G-10 material). 1						
SPECIFICATIONS ($T_J = 25 \text{ °C}$, u	nless otherw	ise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS MIN.		MIN.	TYP.	MAX.	UNI	
Static					•	• • • •		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0, I _D = 25	50 μA	60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, $I_D = 1 \text{ mA}$		-	0.070	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		1.0	-	2.5		
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 10 V$		V	-	-	± 100	nA
		V _{DS} = 60 V, V _{GS} = 0 V		-	-	25		
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 48 V,	$V_{GS} = 0 V,$	T _J = 150 °C	-	-	250	μA
	_	V _{GS} = 10 V	۱ _D	= 21 A ^b	-	0.024	-	_
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.5 V	١ _D	= 15 A ^b	-	0.028	-	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 21 \text{ A}^{\text{b}}$		23	-	-	S	
Dynamic								
Input Capacitance	C _{iss}				-	190		
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	920	-	pF	
Reverse Transfer Capacitance	C _{rss}			_	170	-		
Total Gate Charge	Qg				-	-	66	<u> </u>
Gate-Source Charge	Q _{gs}	$V_{GS} = 5.0 V$ $I_D = 51 A, V_{DS} = 48 V,$		-	-	12	nC	
Gate-Drain Charge	Q _{gd}		see no	g. 6 and 13 ^b	-	-	43	-
Turn-On Delay Time	t _{d(on)}				-	17	-	
Rise Time	t _r	- Vac	= 30 V, I _D =	51 Δ	_	230	-	ns
Turn-Off Delay Time	t _{d(off)}			2, see fig. 10 ^b	_	2	-	
Fall Time	t _f	_		-	110	-	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L _S			-	7.5	-		
Drain-Source Body Diode Characteristic	s	•						•
Continuous Source-Drain Diode Current	١ _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	50 ^c	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	200		
Body Diode Voltage	V _{SD}	$T_J = 25 \ ^\circ C, \ I_S = 51 \ A, \ V_{GS} = 0 \ V^b$		-	-	2.5	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = 51 \text{ A}, dl/dt = 100 \text{ A}/\mu\text{s}^{b}$		-	130	180	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.84	1.3	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is dor	ninated b	vlaand	<u>ا</u> ما

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.
c. Current limited by the package, (Die Current = 51 A).



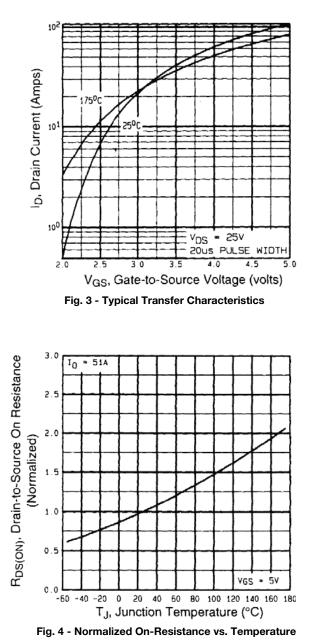


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Fig. 2 - Typical Output Characteristics, T_C = 150 °C





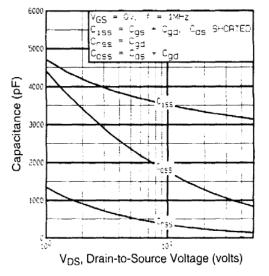


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

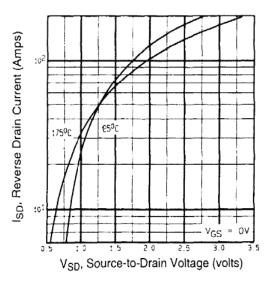
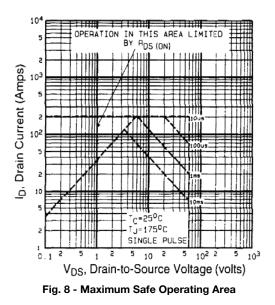


Fig. 7 - Typical Source-Drain Diode Forward Voltage



Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





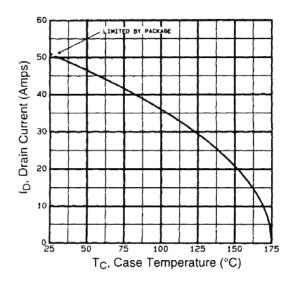


Fig. 9 - Maximum Drain Current vs. Case Temperature

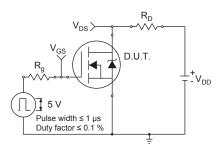


Fig. 10a - Switching Time Test Circuit

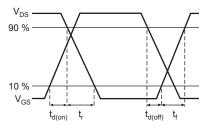
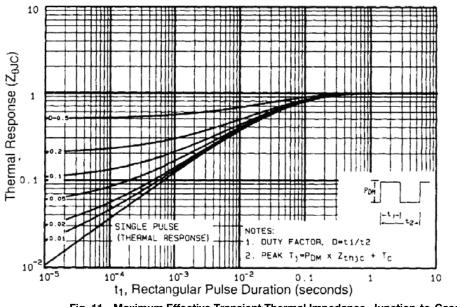


Fig. 10b - Switching Time Waveforms







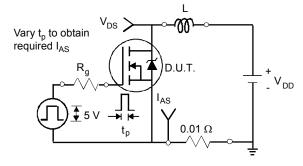


Fig. 12a - Unclamped Inductive Test Circuit

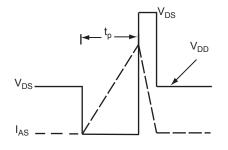


Fig. 12b - Unclamped Inductive Waveforms

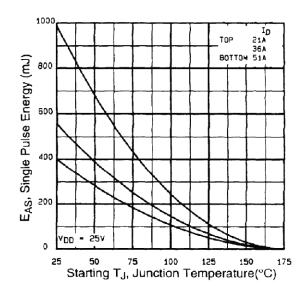


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

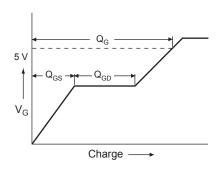


Fig. 13a - Basic Gate Charge Waveform

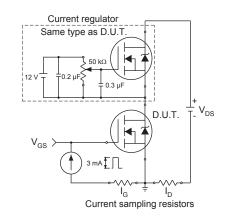
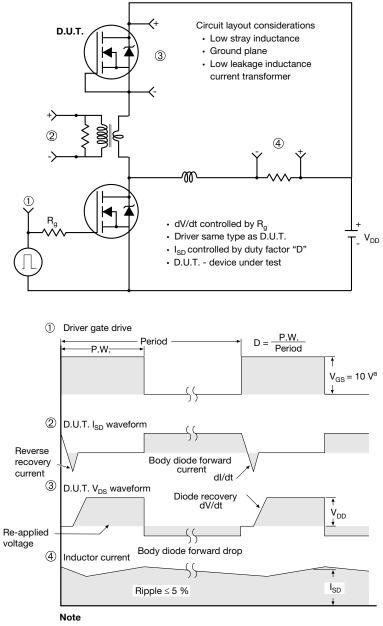


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

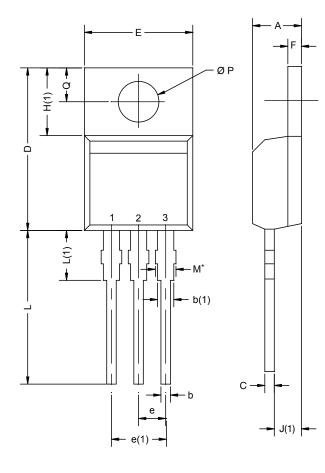


a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



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	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
с	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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